

Analysis of Durability in Replicated Distributed Storage Systems

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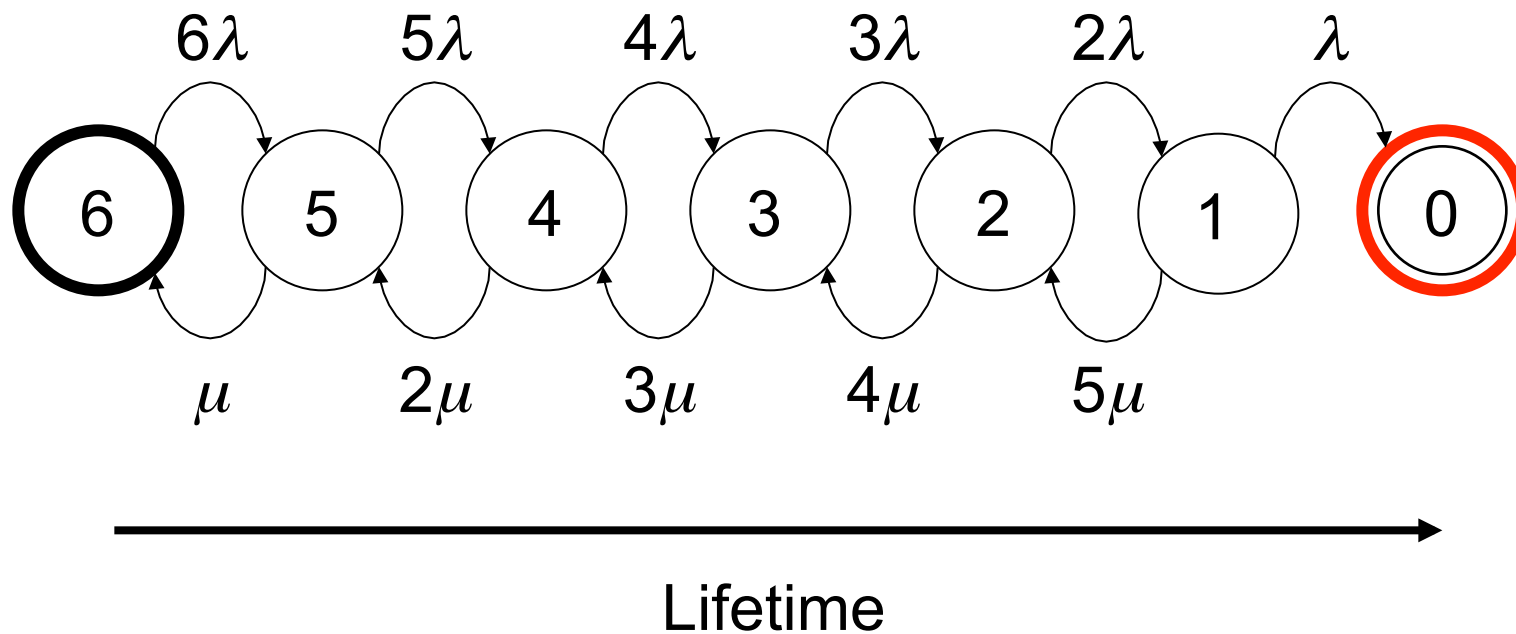
Replication

- Generate/regenerate enough replicas of object so it lives long enough
- Time to repair may be long
 - ◆ Must detect failure, and then regenerate
 - ◆ Repair process itself may fail
 - ◆ Have enough so we never run out
- *Uncertainty whether node is down or dead*

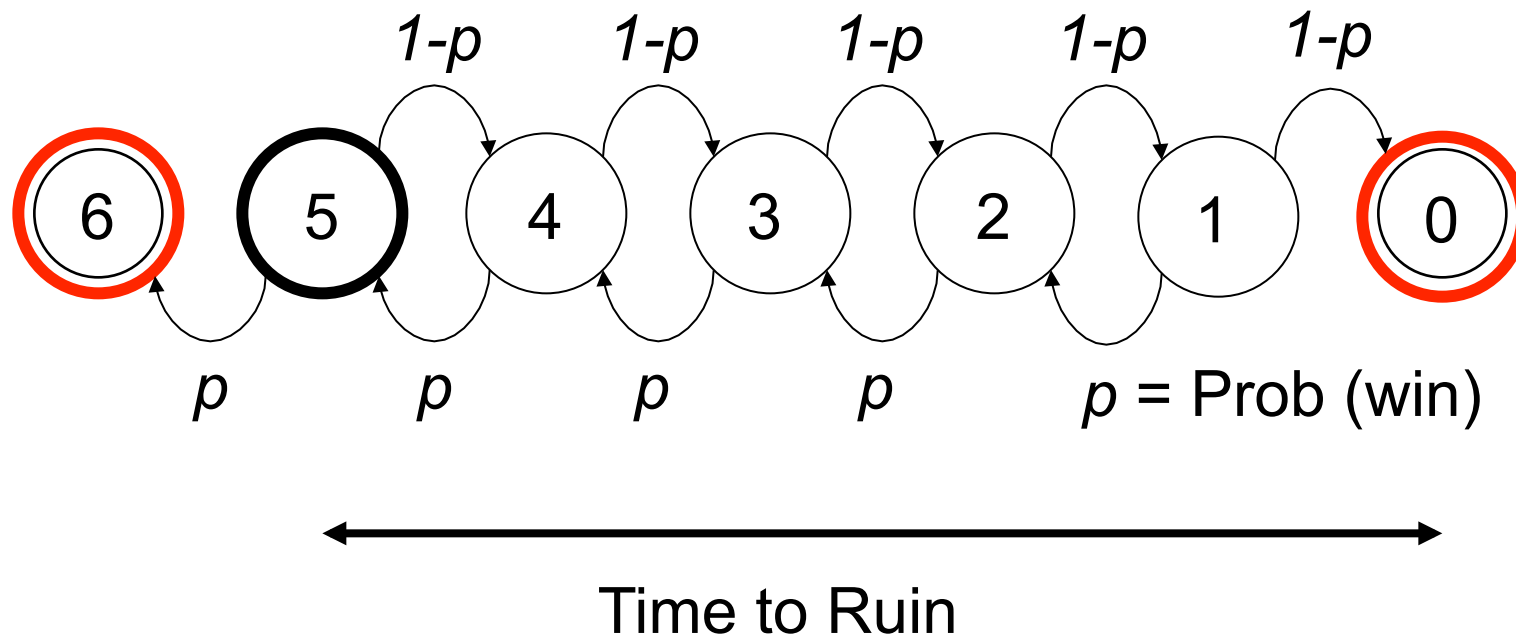
Formulation

- Given expected
 - ◆ Failure rate, λ
 - ◆ Repair rate, μ
 - ◆ Target time to live, L
- How many replicas N to achieve L ?
- Note: *Repairs triggered by failures*

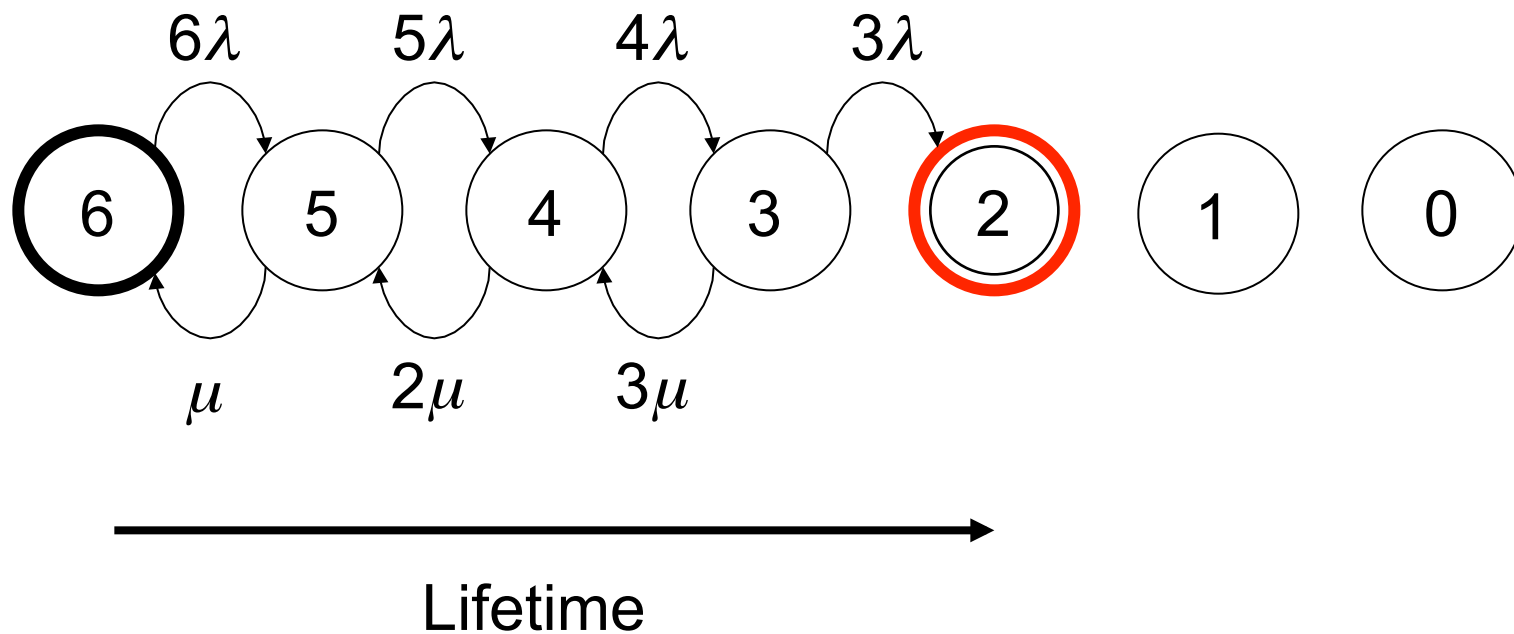
Model For 6 Replicas



Similar to Gambler's Ruin



Erasure Coding: 3 Fragments

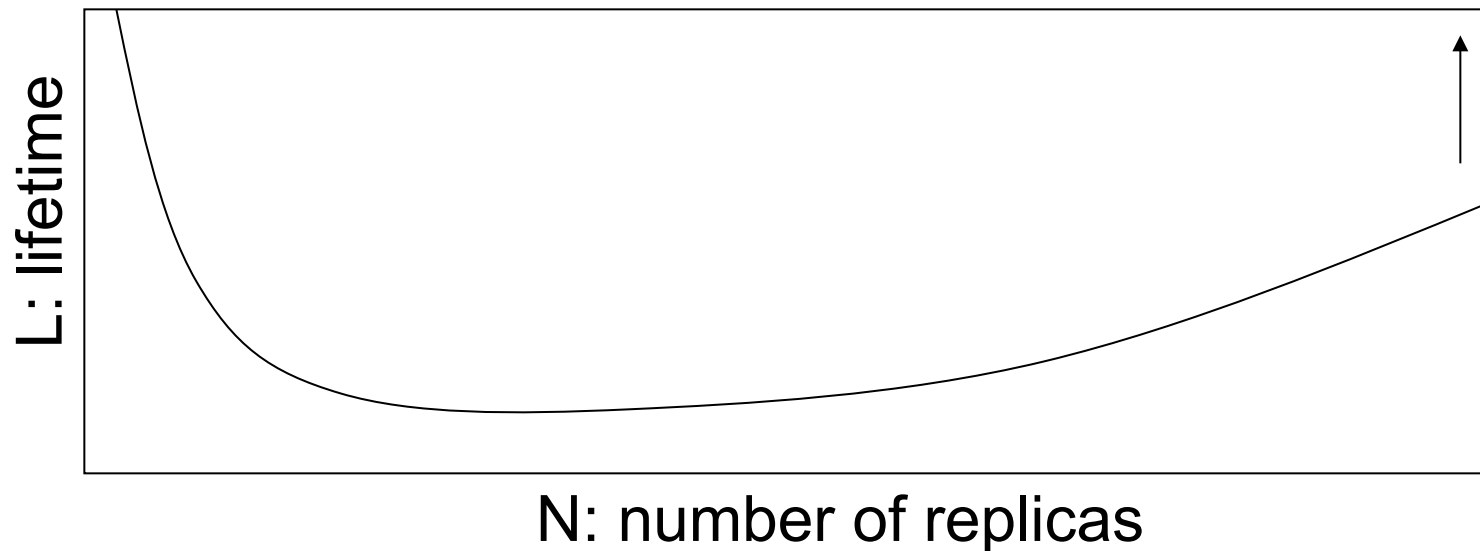


Result: Lifetime

$$L_N = \frac{1}{N\lambda} \sum_{i=0}^{N-1} \sum_{j=0}^i \frac{\binom{N}{j}}{\binom{N-1}{i}} \left(\frac{\mu}{\lambda}\right)^{i-j}$$

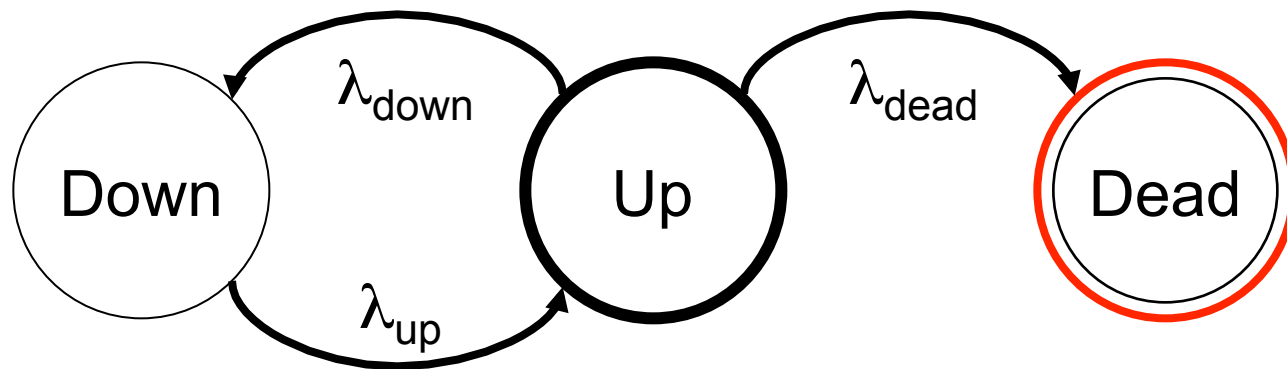
- Increases with N and μ (without bound)
- Question: Which is it better to increase?

Constrained Repair Bandwidth



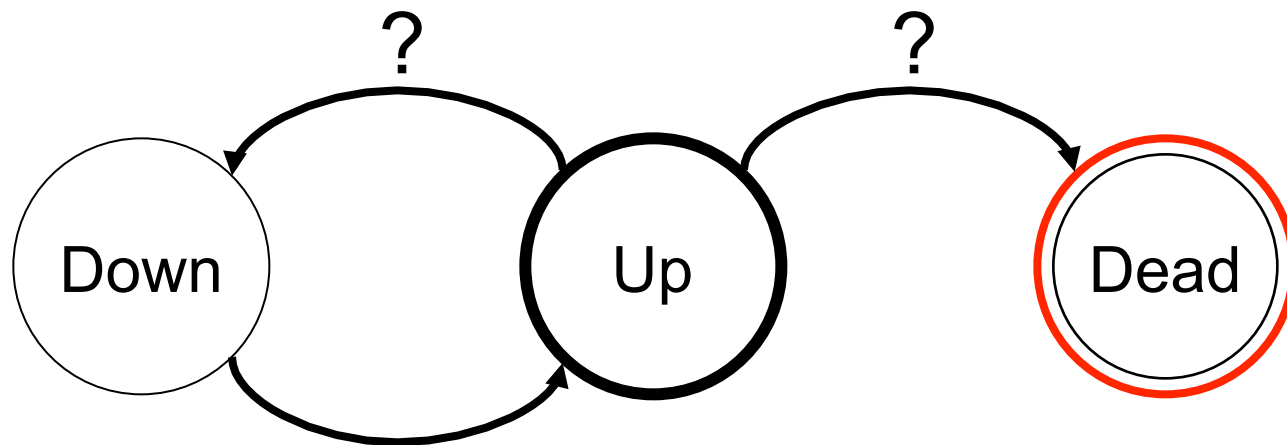
- **Small N**: aggressive repair
- **Large N**: minimal repair

Distinguishing Down / Dead



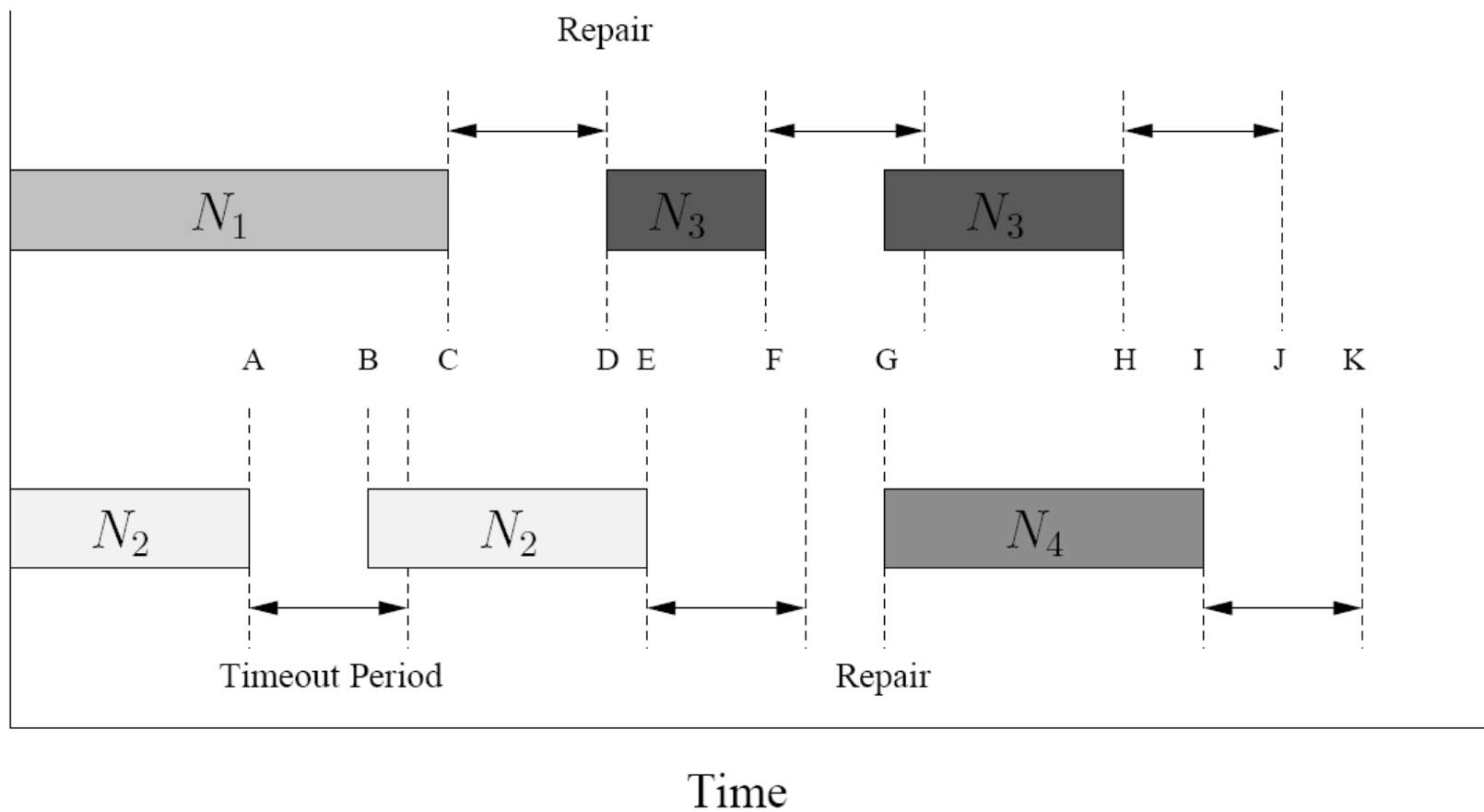
- Assumptions for single node, $T \gg d$
 - ◆ lifetime $\sim \exp(T)$ $\lambda_{\text{dead}} = (u+d)/uT$
 - ◆ uptime $\sim \exp(u)$ $\lambda_{\text{up}} = 1/d$
 - ◆ downtime $\sim \exp(d)$ $\lambda_{\text{down}} = (T-u-d)/uT$

Uncertainty: Down or Dead

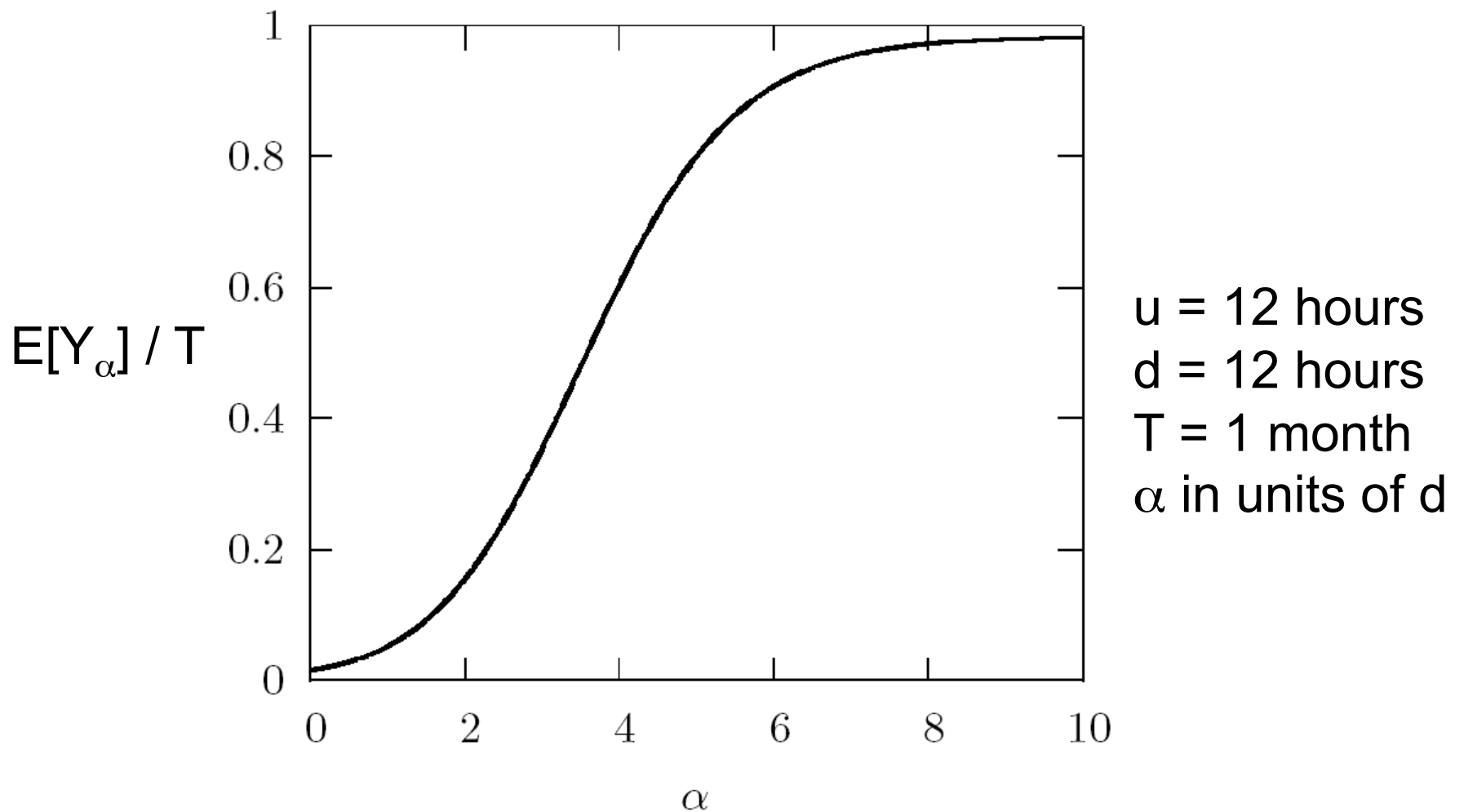


- Timeout α
 - ◆ If node not up after α , declare dead, repair
 - ◆ What value of α maximizes efficiency?

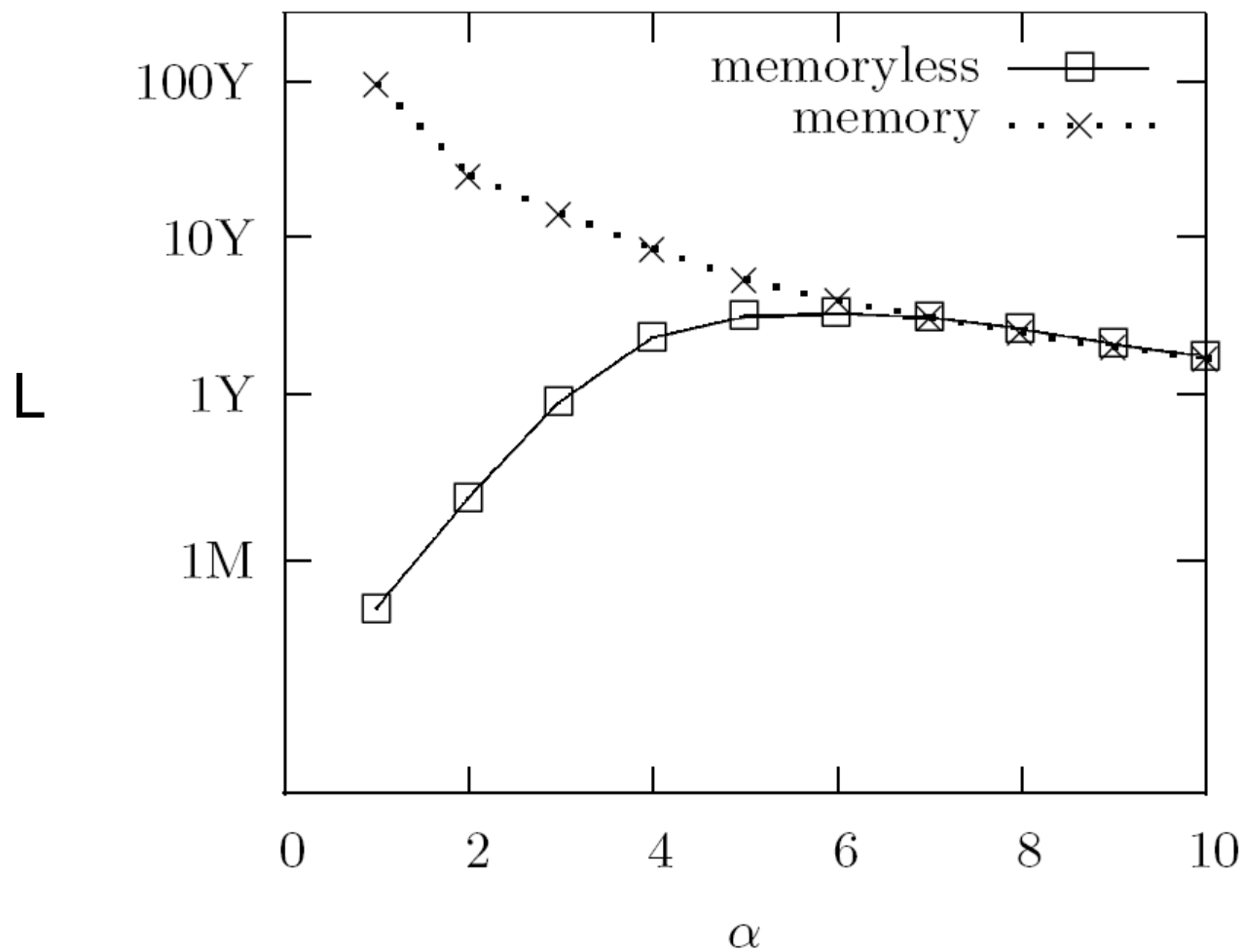
Ex: Number of replicas $r=2$



$E[Y_\alpha]$ = Replica Mean Timeout



Lifetime L vs. α , $r = 4$



Conclusions

- There is an optimal timeout
- Can be determined by observing a single node
- Without-memory performs close to with-memory